4,194,304 WORD × 1 BIT DYNAMIC RAM

PRELIMINARY

DESCRIPTION

The TC514100AP/AJ/ASJ/AZ is the new generation dynamic RAM organized 4,194,304 words by 1 bit. The TC514100AP/AJ/ASJ/AZ utilizes TOSHIBA's CMOS Silicon gate process technology as well as advanced circuit techniques to provide wide operating margins, both internally and to the system user.

Multiplexed address inputs permit the TC514100AP/AJ/ASJ/AZ to be packaged in a standard 18 pin plastic DIP, 26/20 pin plastic SOJ (300/350mil) and 20 pin plastic ZIP. The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment. System oriented features include single power supply of 5V±10% tolerance, direct interfacing capability with high performance logic families such as Schottky TTL.

FEATURES

- 4,194,304 word by 1bit organization
- Fast access time and cycle time

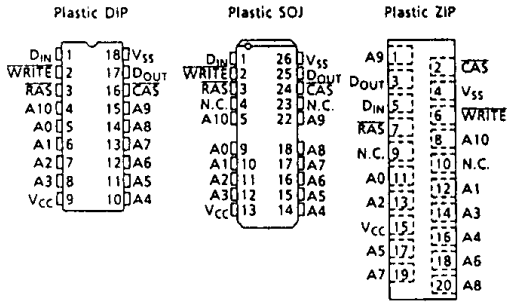
	TC514100AP/AJ/ASJ/AZ - 70/80/10		
t_{RAC} $\overline{RAS}$ Access Time	70ns	80ns	100ns
t_{AA} Column Address Access Time	35ns	40ns	50ns
t_{CAC} $\overline{CAS}$ Access Time	20ns	20ns	25ns
t_{RC} Cycle Time	130ns	150ns	180ns
t_{PC} Fast Page Mode Cycle Time	45ns	50ns	60ns

- Single power supply of 5V±10% with a built-in V_{BB} generator
- Low Power
  - 550mW MAX. Operating (TC514100AP/AJ/ASJ/AZ-70)
  - 468mW MAX. Operating (TC514100AP/AJ/ASJ/AZ-80)
  - 413mW MAX. Operating (TC514100AP/AJ/ASJ/AZ-10)
  - 5.5mW MAX. Standby
- Outputs unlatched at cycle end allows two-dimensional chip selection
- Common I/O capability using "EARLY WRITE" operation
- Read-Modify-Write, $\overline{CAS}$ before $\overline{RAS}$ refresh, $\overline{RAS}$-only refresh, Hidden refresh, Fast Page Mode and Test Mode capability
- All inputs and outputs TTL compatible
- 1024 refresh cycles/16ms
- Package TC514100AP : DIP18-P-300E
  TC514100AJ : SOJ26-P-350
  TC514100ASJ : SOJ26-P-300A
  TC514100AZ : ZIP20-P-400A

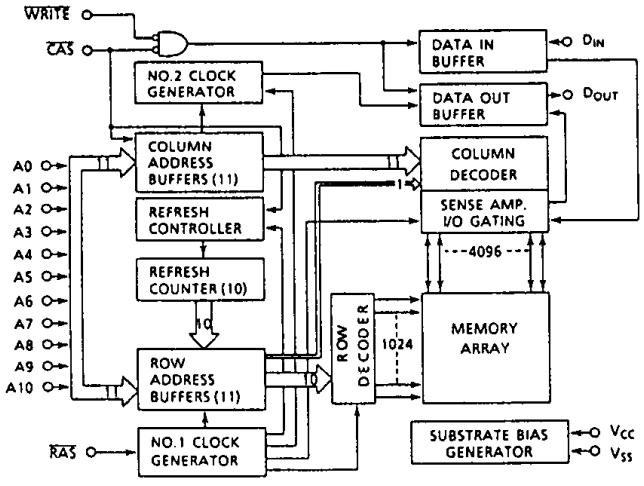
PIN NAMES

A0~A10	Address Inputs	$\overline{WRITE}$	Read/Write Input
$\overline{RAS}$	Row Address Strobe	V_{CC}	Power (+5V)
D_{IN}	Data In	V_{SS}	Ground
D_{OUT}	Data Out	N.C.	No Connection
$\overline{CAS}$	Column Address Strobe		

PIN CONNECTION (TOP VIEW)



BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

ITEM	SYMBOL	RATING	UNITS	NOTES
Input Voltage	V_{IN}	-1~7	V	1
Output Voltage	V_{OUT}	-1~7	V	1
Power Supply Voltage	V_{CC}	-1~7	V	1
Operating Temperature	T_{OPR}	0~70	°C	1
Storage Temperature	T_{STG}	-55~150	°C	1
Soldering Temperature · Time	T_{SOLDER}	260 · 10	°C · sec	1
Power Dissipation	P_D	700	mW	1
Short Circuit Output Current	I_{OUT}	50	mA	1

RECOMMENDED DC OPERATING CONDITIONS (Ta = 0~70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT	NOTES
V_{CC}	Supply Voltage	4.5	5.0	5.5	V	2
V_{IH}	Input High Voltage	2.4	-	6.5	V	2
V_{IL}	Input Low Voltage	-1.0	-	0.8	V	2

DC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V ± 10%, Ta = 0~70°c)

SYMBOL	PARAMETER		MIN.	MAX.	UNITS	NOTES
I_{CC1}	OPERATING CURRENT Average Power Supply Operating Current ($\overline{RAS}$, $\overline{CAS}$, Address Cycling: t_{RC} = t_{RC} MIN.)	TC514100AP/AJ/ASJ/AZ-70	–	100	mA	3, 4
		TC514100AP/AJ/ASJ/AZ-80	–	85		5
		TC514100AP/AJ/ASJ/AZ-10	–	75		
I_{CC2}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS}$ = $\overline{CAS}$ = V_{IH})		–	2	mA	
I_{CC3}	$\overline{RAS}$ ONLY REFRESH CURRENT Average Power Supply Current, $\overline{RAS}$ Only Mode ($\overline{RAS}$ Cycling, $\overline{CAS}$ = V_{IH}: t_{RC} = t_{RC} MIN.)	TC514100AP/AJ/ASJ/AZ-70	–	100	mA	3,5
		TC514100AP/AJ/ASJ/AZ-80	–	85		
		TC514100AP/AJ/ASJ/AZ-10	–	75		
I_{CC4}	FAST PAGE MODE CURRENT Average Power Supply Current, Fast Page Mode ($\overline{RAS}$ = V_{IL}, $\overline{CAS}$, Address Cycling: t_{PC} = t_{PC} MIN.)	TC514100AP/AJ/ASJ/AZ-70	–	60	mA	3, 4
		TC514100AP/AJ/ASJ/AZ-80	–	50		5
		TC514100AP/AJ/ASJ/AZ-10	–	45		
I_{CC5}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS}$ = $\overline{CAS}$ = V_{CC} – 0.2V)		–	1	mA	
I_{CC6}	$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH CURRENT Average Power Supply Current, $\overline{CAS}$ Before $\overline{RAS}$ Mode ($\overline{RAS}$, $\overline{CAS}$ Cycling: t_{RC} = t_{RC} MIN.)	TC514100AP/AJ/ASJ/AZ-70	–	100	mA	3,5
		TC514100AP/AJ/ASJ/AZ-80	–	85		
		TC514100AP/AJ/ASJ/AZ-10	–	75		
$I_{I(L)}$	INPUT LEAKAGE CURRENT Input Leakage Current, any input (0V ≦ V_{IN} ≦ 6.5V, All Other Pins Not Under Test = 0V)		– 10	10	μA	
$I_{O(L)}$	OUTPUT LEAKAGE CURRENT (D_{OUT} is disabled, 0V ≦ V_{OUT} ≦ 5.5V)		– 10	10	μA	
V_{OH}	OUTPUT LEVEL Output "H" Level Voltage (I_{OUT} = – 5mA)		2.4	–	V	
V_{OL}	OUTPUT LEVEL Output "L" Level Voltage (I_{OUT} = 4.2mA)		–	0.4	V	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(V_{CC} = 5V ± 10%, Ta = 0~70°c)(Notes 6, 7, 8)

SYMBOL	PARAMETER	TC514100AP/ AJ/ASJ/AZ-70		TC514100AP/ AJ/ASJ/AZ-80		TC514100AP/ AJ/ASJ/AZ-10		UNIT	NOTES
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
t_{RC}	Random Read or Write Cycle Time	130	-	150	-	180	-	ns	
t_{RMW}	Read-Modify-Write Cycle Time	155	-	175	-	210	-	ns	
t_{PC}	Fast Page Mode Cycle Time	45	-	50	-	60	-	ns	
t_{PRMW}	Fast Page Mode Read-Modify-Write Cycle Time	70	-	75	-	90	-	ns	
t_{RAC}	Access Time from $\overline{RAS}$	-	70	-	80	-	100	ns	9, 14 15
t_{CAC}	Access Time from $\overline{CAS}$	-	20	-	20	-	25	ns	9, 14
t_{AA}	Access Time from Column Address	-	35	-	40	-	50	ns	9, 15
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	-	40	-	45	-	55	ns	9
t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	-	0	-	0	-	ns	9
t_{OFF}	Output Buffer Turn-off Delay	0	20	0	20	0	20	ns	10
t_T	Transition Time (Rise and Fall)	3	50	3	50	3	50	ns	8
t_{RP}	$\overline{RAS}$ Precharge Time	50	-	60	-	70	-	ns	
t_{RAS}	$\overline{RAS}$ Pulse Width	70	10,000	80	10,000	100	10,000	ns	
t_{RASP}	$\overline{RAS}$ Pulse Width (Fast Page Mode)	70	200,000	80	200,000	100	200,000	ns	
t_{RSH}	$\overline{RAS}$ Hold Time	20	-	20	-	25	-	ns	
t_{RHCP}	$\overline{RAS}$ Hold Time From $\overline{CAS}$ Precharge (Fast Page Mode)	40	-	45	-	55	-	ns	
t_{CSH}	$\overline{CAS}$ Hold Time	70	-	80	-	100	-	ns	
t_{CAS}	$\overline{CAS}$ Pulse Width	20	10,000	20	10,000	25	10,000	ns	
t_{RCD}	$\overline{RAS}$ to $\overline{CAS}$ Delay Time	20	50	20	60	25	75	ns	14
t_{RAD}	$\overline{RAS}$ to Column Address Delay Time	15	35	15	40	20	50	ns	15
t_{CRP}	$\overline{CAS}$ to $\overline{RAS}$ Precharge Time	5	-	5	-	10	-	ns	
t_{CP}	$\overline{CAS}$ Precharge Time	10	-	10	-	10	-	ns	
t_{ASR}	Row Address Set-Up Time	0	-	0	-	0	-	ns	
t_{RAH}	Row Address Hold Time	10	-	10	-	15	-	ns	
t_{ASC}	Column Address Set-Up Time	0	-	0	-	0	-	ns	
t_{CAH}	Column Address Hold Time	15	-	15	-	20	-	ns	
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	35	-	40	-	50	-	ns	
t_{RCS}	Read Command Set-Up Time	0	-	0	-	0	-	ns	
t_{RCH}	Read Command Hold Time	0	-	0	-	0	-	ns	11
t_{RRH}	Read Command Hold Time referenced to $\overline{RAS}$	0	-	0	-	0	-	ns	11
t_{WCH}	Write Command Hold Time	15	-	15	-	20	-	ns	

ELECTRICAL CHARACTGERISTICS AND RECOMMENDED AC OPERATING CONDITIONS
(Continued)

SYMBOL	PARAMETER	TC514100AP/ AJ/ASJ/AZ-70		TC514100AP/ AJ/ASJ/AZ-80		TC514100AP/ AJ/ASJ/AZ-10		UNITS	NOTES
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
t_{WP}	Write Command Pulse Width	15	-	15	-	20	-	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	20	-	20	-	25	-	ns	
t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	20	-	20	-	25	-	ns	
t_{DS}	Data Set-Up Time	0	-	0	-	0	-	ns	12
t_{DH}	Data Hold Time	15	-	15	-	20	-	ns	12
t_{REF}	Refresh Period	-	16	-	16	-	16	ms	
t_{WCS}	Write Command Set-UP Time	0	-	0	-	0	-	ns	13
t_{CWD}	$\overline{CAS}$ to $\overline{WRITE}$ Delay Time	20	-	20	-	25	-	ns	13
t_{RWD}	$\overline{RAS}$ to $\overline{WRITE}$ Delay Time	70	-	80	-	100	-	ns	13
t_{AWD}	Column Address to $\overline{WRITE}$ Delay Time	35	-	40	-	50	-	ns	13
t_{CPWD}	$\overline{CAS}$ Precharge to $\overline{WRITE}$ Delay Time	40	-	45	-	55	-	ns	13
t_{CSR}	$\overline{CAS}$ Set-Up Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	5	-	5	-	5	-	ns	
t_{CHR}	$\overline{CAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	15	-	15	-	20	-	ns	
t_{RPC}	$\overline{RAS}$ to $\overline{CAS}$ Precharge Time	0	-	0	-	0	-	ns	
t_{CPT}	$\overline{CAS}$ Precharge Time ($\overline{CAS}$ before $\overline{RAS}$ Counter Test Cycle)	40	-	40	-	50	-	ns	
t_{WTS}	Write Command Set-Up Time (Test Mode In)	10	-	10	-	10	-	ns	
t_{WTH}	Write Command Hold Time (Test Mode In)	10	-	10	-	10	-	ns	
t_{WRP}	$\overline{WRITE}$ to $\overline{RAS}$ Precharge Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	10	-	10	-	10	-	ns	
t_{WRH}	$\overline{WRITE}$ to $\overline{RAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	10	-	10	-	10	-	ns	

ELECTRICAL CHARACTGERISTICS AND RECOMMENDED AC OPERATING CONDITIONS IN THE TEST MODE

(V_{CC} = 5V ± 10%, Ta = 0~70°C) (Notes 6, 7, 8)

SYMBOL	PARAMETER	TC514100AP/ AJ/ASJ/AZ-70		TC514100AP/ AJ/ASJ/AZ-80		TC514100AP/ AJ/ASJ/AZ-10		UNIT	NOTES
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
t_{RC}	Random Read Write Cycle Time	135	-	155	-	185	-	ns	
t_{RMW}	Read-Modify-Write Cycle Time	160	-	180	-	215	-		
t_{PC}	Fast Page Mode Cycle Time	50	-	55	-	65	-	ns	
t_{PRMW}	Fast Page Mode Read-Modify-Write Cycle Time	75	-	80	-	95	-	ns	13
t_{RAC}	Access Time from $\overline{RAS}$	-	75	-	85	-	105	ns	9, 14, 15
t_{CAC}	Access Time from $\overline{CAS}$	-	25	-	25	-	30	ns	9, 14
t_{AA}	Access Time from Column Address	-	40	-	45	-	55	ns	9, 15
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	-	45	-	50	-	60	ns	9
t_{RAS}	$\overline{RAS}$ Pulse Width	75	10,000	85	10,000	105	10,000	ns	
t_{RASP}	$\overline{RAS}$ Pulse Width (Fast Page Mode)	75	200,000	85	200,000	105	200,000	ns	
t_{RSH}	$\overline{RAS}$ Hold Time	25	-	25	-	30	-	ns	
t_{CSH}	$\overline{CAS}$ Hold Time	75	-	85	-	105	-	ns	
t_{RHCP}	$\overline{CAS}$ Prechrge to $\overline{RAS}$ Hold Time	45	-	50	-	60	-	ns	
t_{CAS}	$\overline{CAS}$ Pulse Width	25	10,000	25	10,000	30	10,000	ns	
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	40	-	45	-	55	-	ns	
t_{CWD}	$\overline{CAS}$ to $\overline{WRITE}$ Delay Time	25	-	25	-	30	-	ns	13
t_{RWD}	$\overline{RAS}$ to $\overline{WRITE}$ Delay Time	75	-	85	-	105	-	ns	13
t_{AWD}	Column Address to $\overline{WRITE}$ Delay Time	40	-	45	-	55	-	ns	13
t_{CPWD}	$\overline{CAS}$ Precharge to $\overline{WRITE}$ Delay Time	45	-	50	-	60	-	ns	13

CAPACITANCE (V_{CC} = 5V ± 10%, f = 1MHz, Ta = 0~70°C)

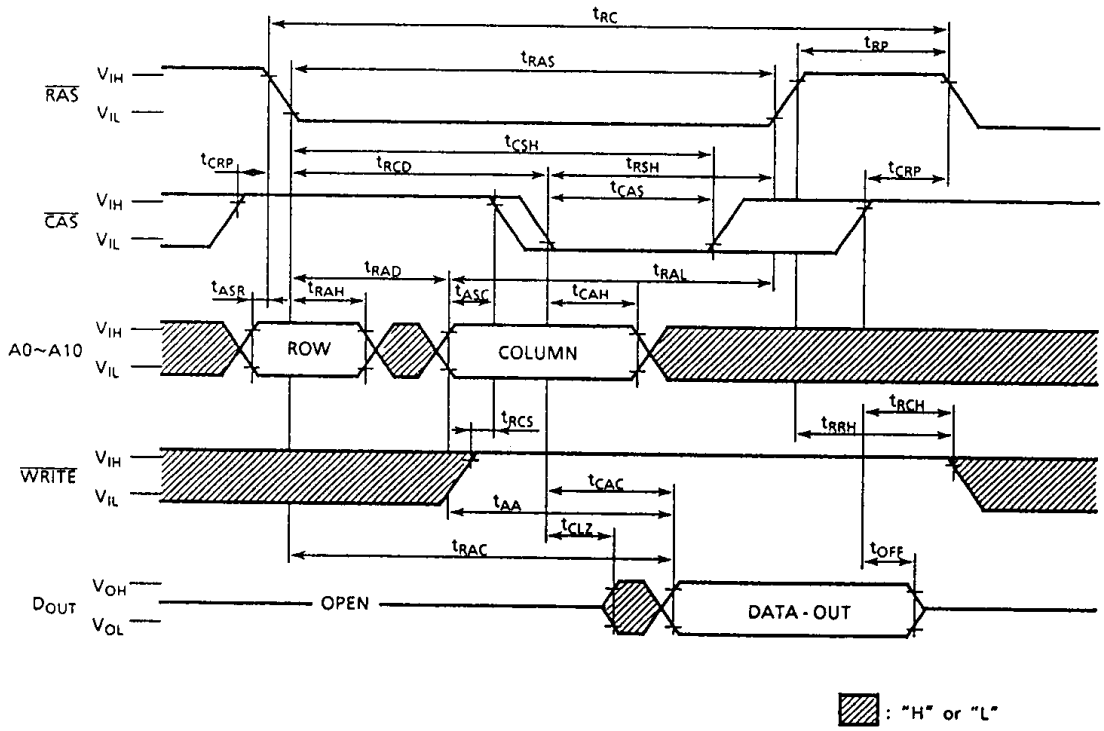
SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C_{I1}	Input Capacitance (A0~A10, D_{IN})	-	5	pF
C_{I2}	Input Capacitance ($\overline{RAS}$, $\overline{CAS}$, $\overline{WRITE}$)	-	7	
C_O	Output Capacitance (D_{OUT})	-	7	

NOTES:

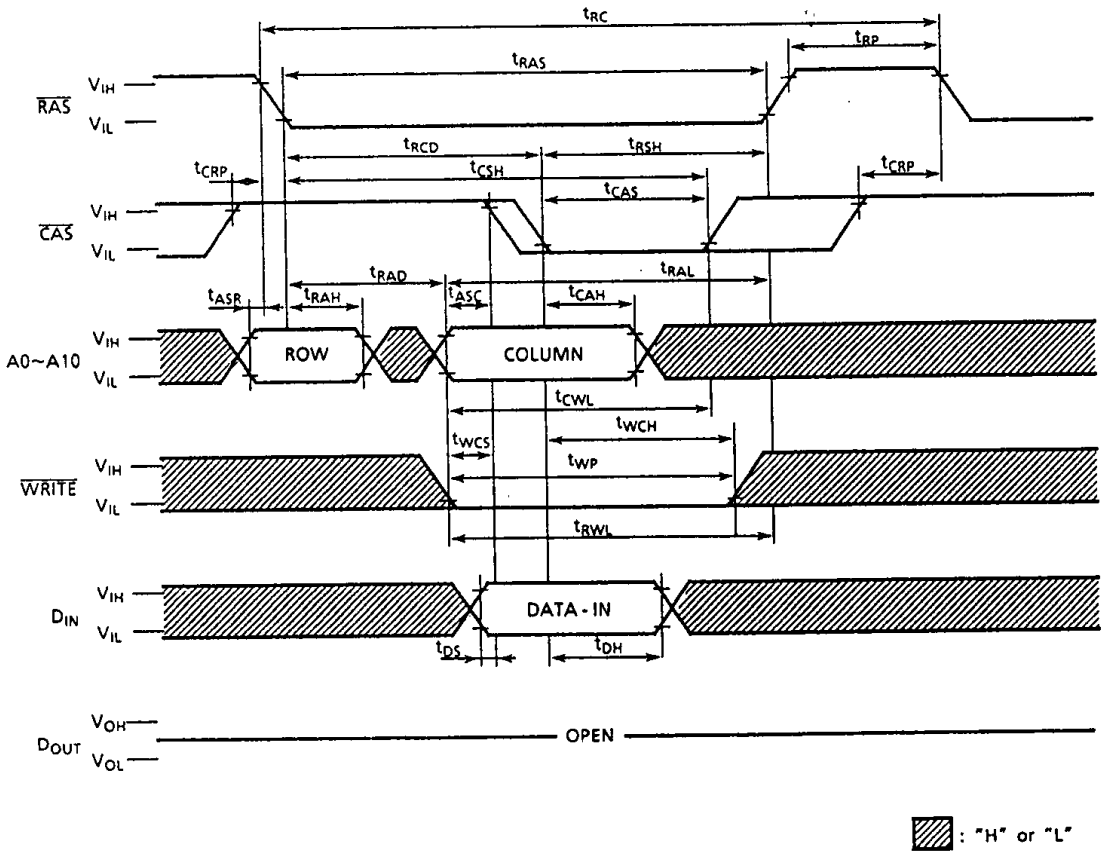
1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.
2. All voltages are referenced to V_{SS}.
3. I_{CC1}, I_{CC3}, I_{CC4}, I_{CC6} depend on cycle rate.
4. I_{CC1}, I_{CC4} depend on output loading. Specified values are obtained with the output open.
5. Column address can be changed once or less While $\overline{RAS} = V_{IL}$ and $\overline{CAS} = V_{IH}$.
6. An initial pause of 200μs is required after power-up followed by 8 $\overline{RAS}$ only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{CAS}$ before $\overline{RAS}$ refresh cycles instead of 8 $\overline{RAS}$ only refresh cycles are required.
7. AC measurements assume $t_T = 5ns$.
8. V_{IH} (min.) and V_{IL} (max.) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL}.
9. Measured with a load equivalent to 2 TTL loads and 100pF.
10. t_{OFF} (max.) defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
12. These parameters are referenced to $\overline{CAS}$ leading edge in early write cycles and to $\overline{WRITE}$ leading edge in Read-Modify-Write cycles.
13. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD} and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geqq t_{WCS}$ (min.), the cycle is an early write cycle and data out pin will remain open circuit (high impedance) throughout the entire cycle; If $t_{RWD} \geqq t_{RWD}$ (min.), $t_{CWD} \geqq t_{CWD}$ (min.), $t_{AWD} \geqq t_{AWD}$ (min.) and $t_{CPWD} \geqq t_{CPWD}$ (min.) (Fast Page Mode), the cycle is a Read-Modify-Write cycle and the data out will contain data read from the selected cell: If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
14. Operation within the t_{RCD} (max.) limit insures that t_{RAC} (max.) can be met. t_{RCD} (max.) is specified as a reference point only: If t_{RCD} is greater than the specified t_{RCD} (max.) limit, then access time is controlled by t_{CAC}.
15. Operation within the t_{RAD} (max.) limit insures that t_{RAC} (max.) can be met. t_{RAD} (max.) is specified as a reference point only: If t_{RAD} is greater than the specified t_{RAD} (max.) limit, then access time is controlled by t_{AA}.

TIMING WAVEFORMS

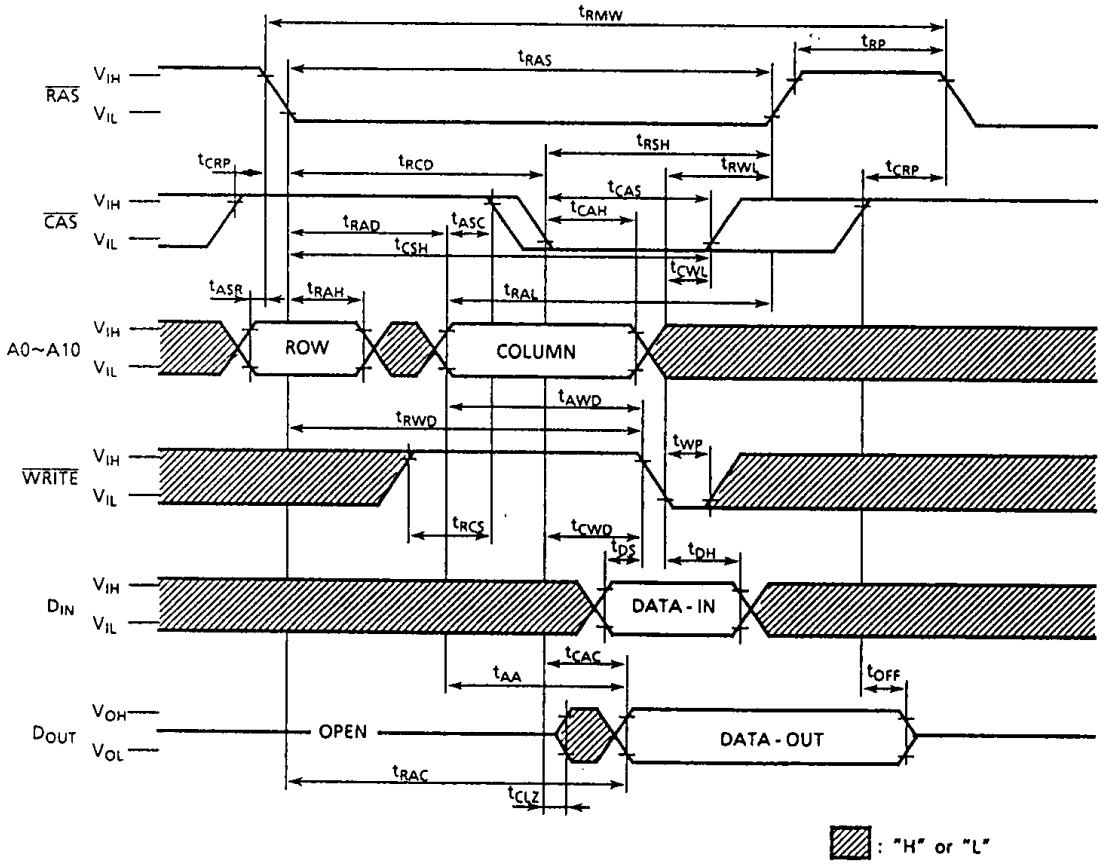
READ CYCLE



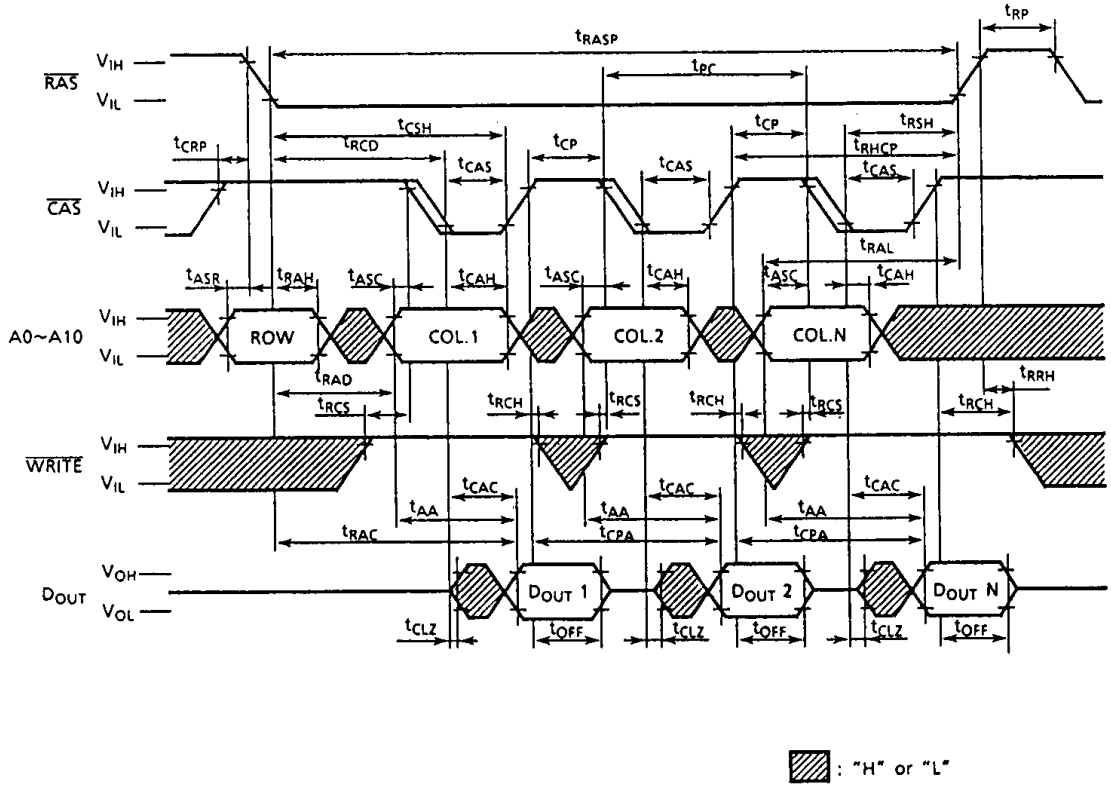
WRITE CYCLE (EARLY WRITE)



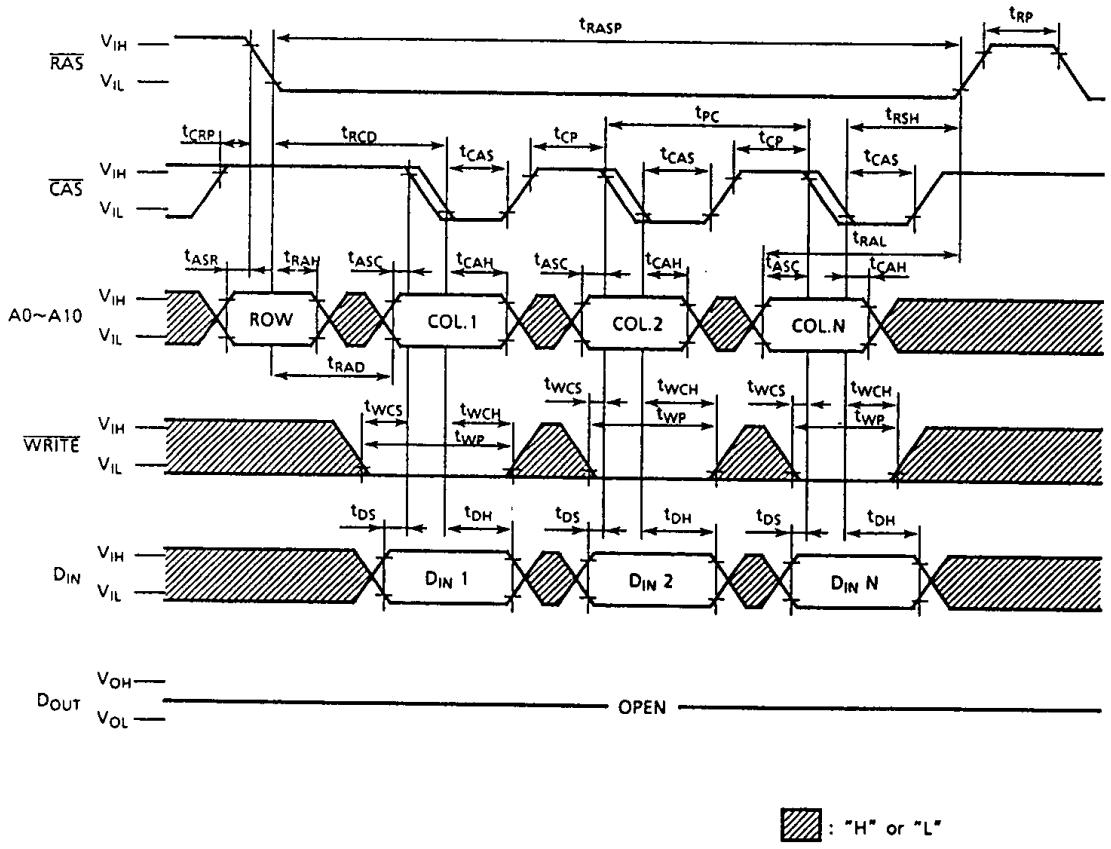
READ-MODIFY-WRITE CYCLE



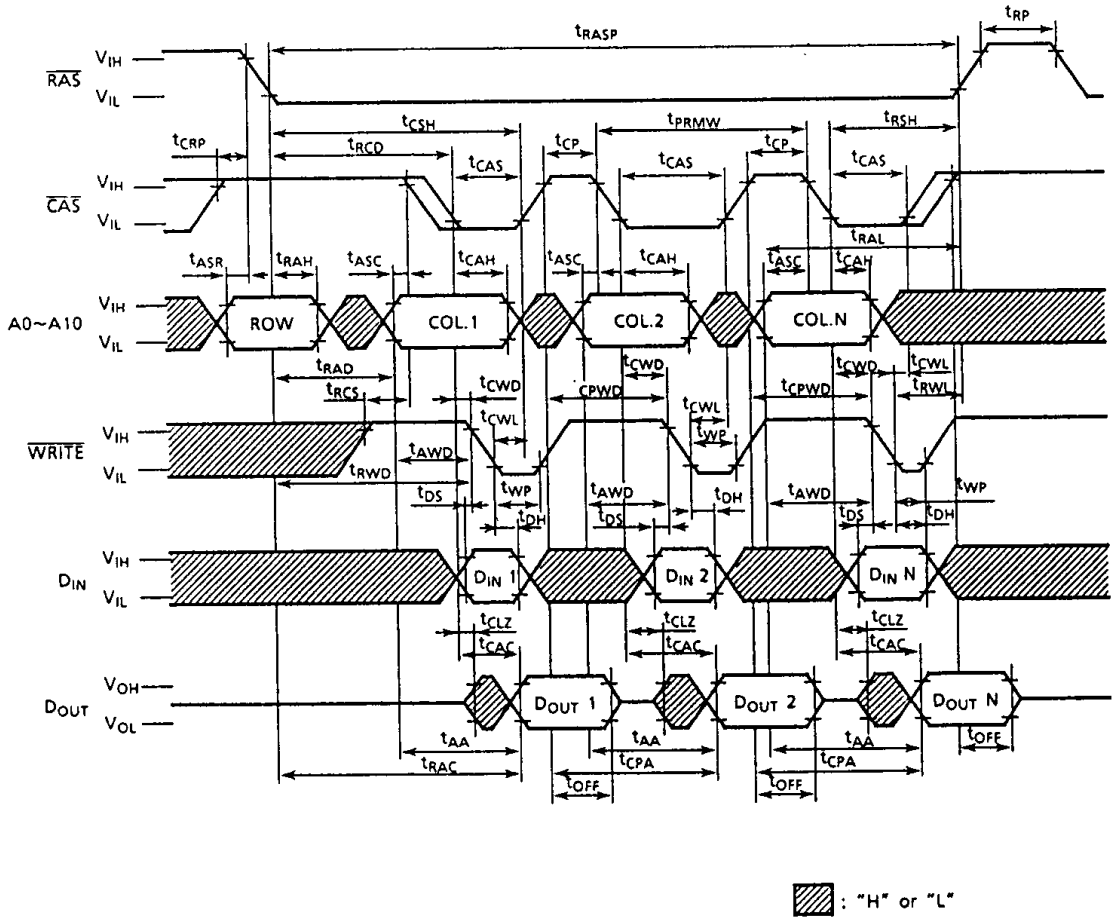
FAST PAGE MODE READ CYCLE



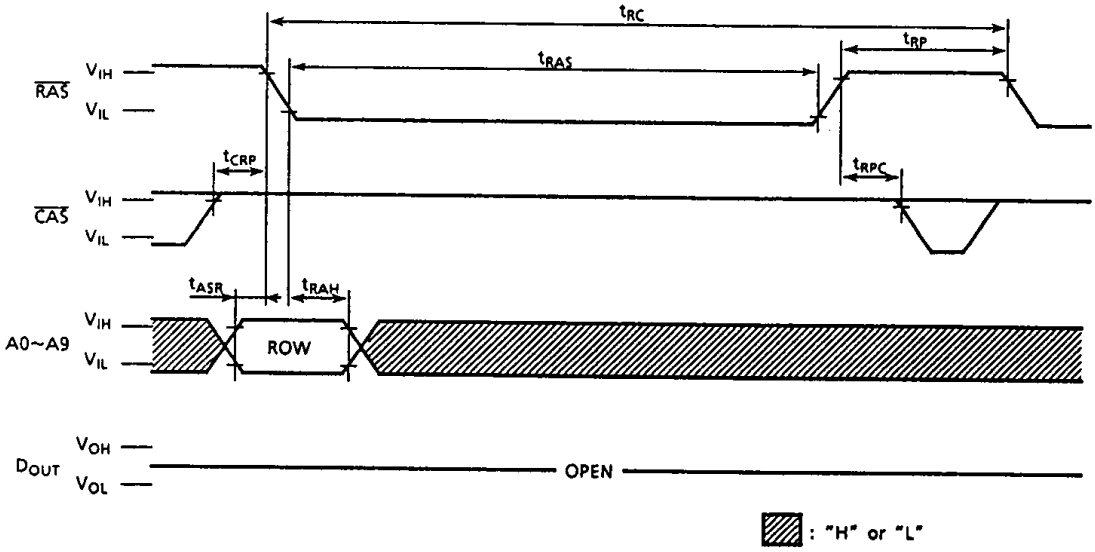
FAST PAGE MODE WRITE CYCLE (EARLY WRITE)



FAST PAGE MODE READ-MODIFY-WRITE CYCLE

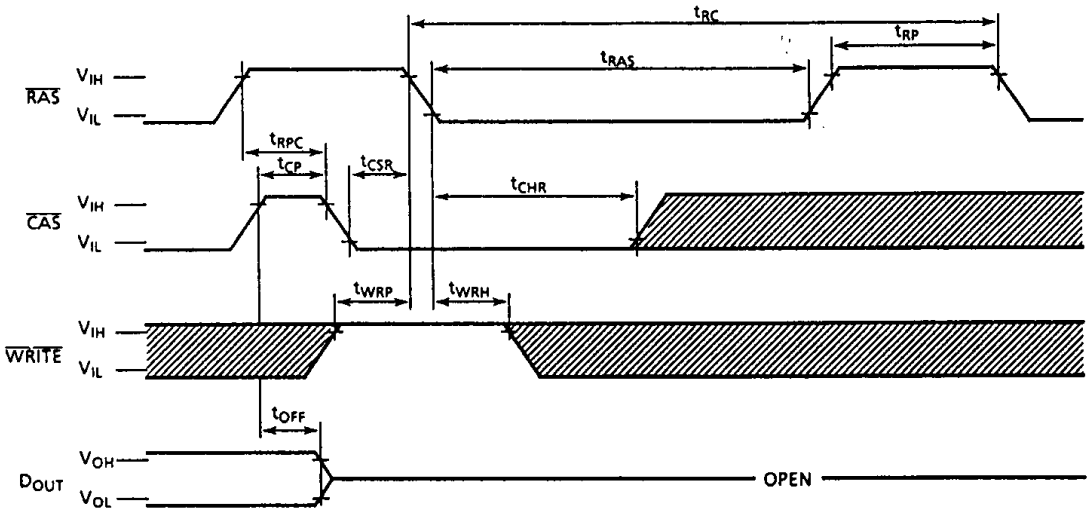


$\overline{RAS}$ ONLY REFRESH CYCLE



Note: $\overline{WRITE}$, A10 = "H" or "L"

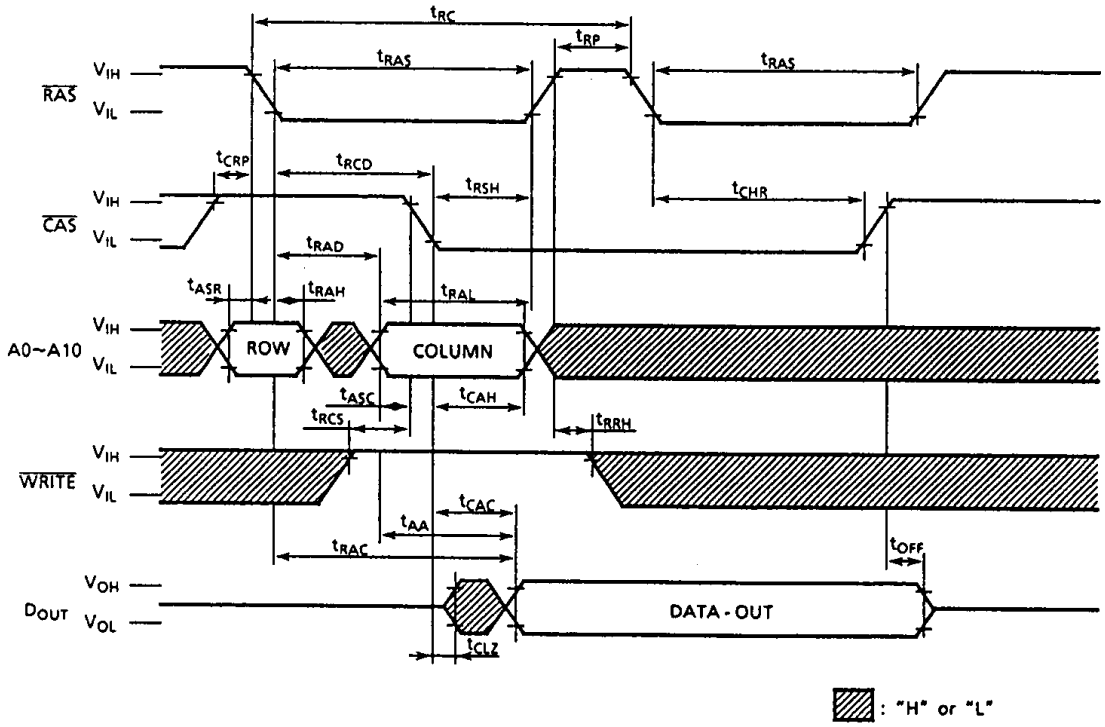
$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH CYCLE



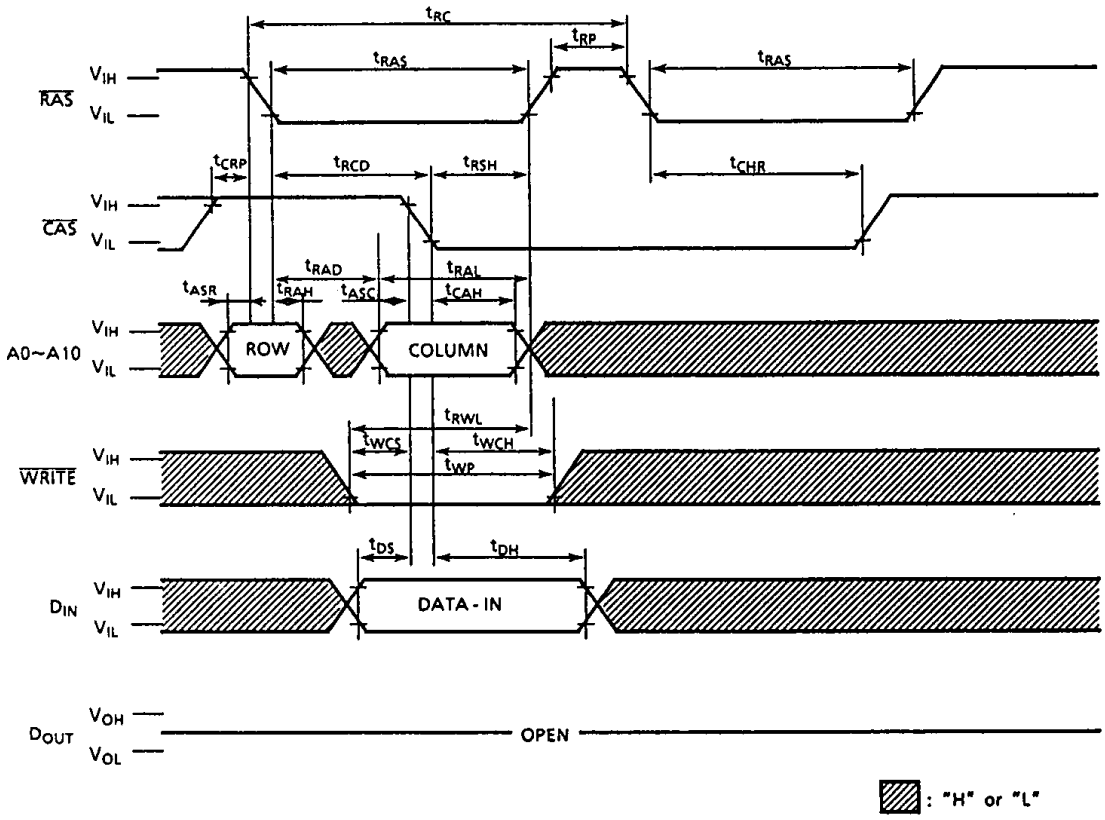
Note : A0~A10 = "H" or "L"

▨ : "H" or "L"

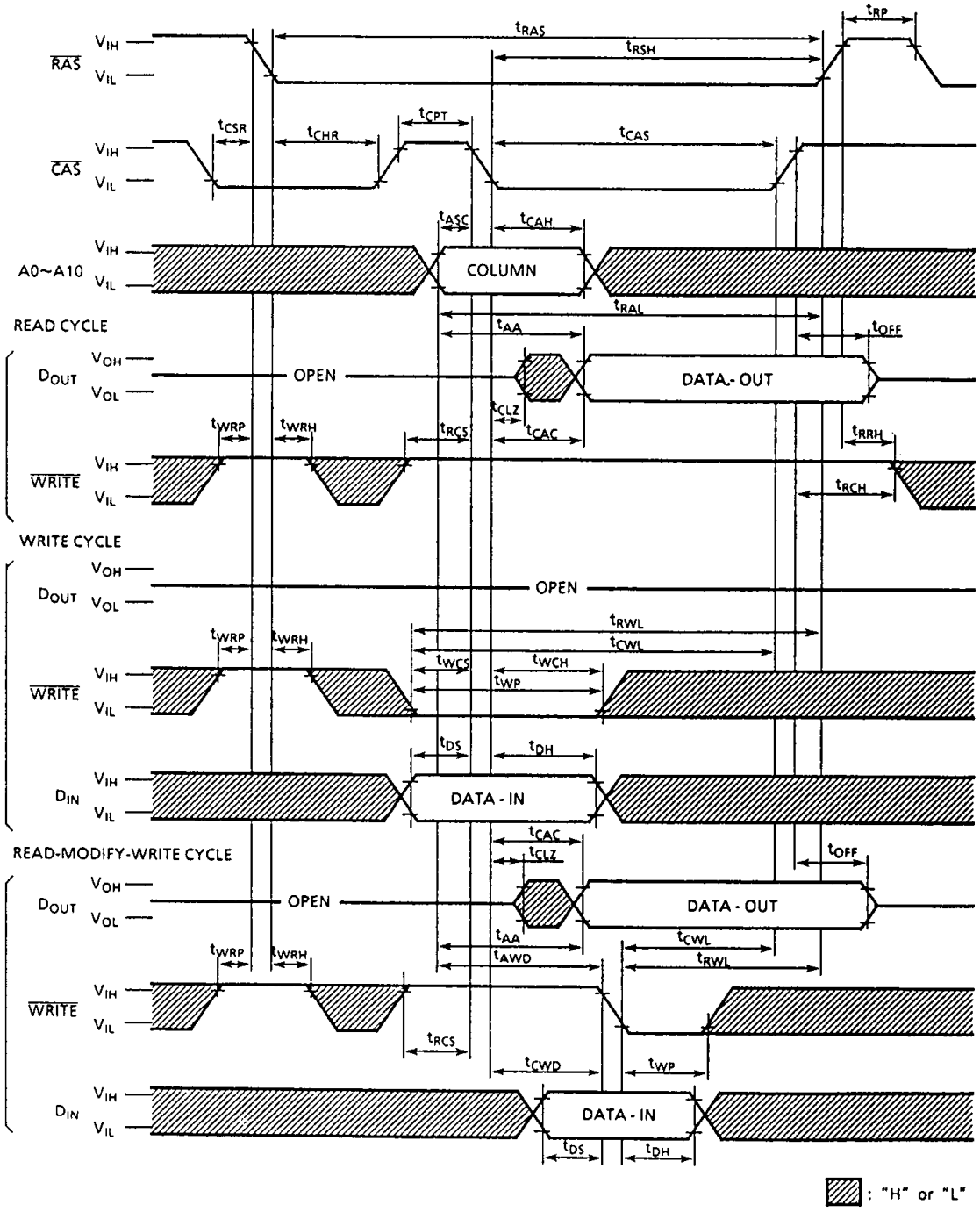
HIDDEN REFRESH CYCLE (READ)



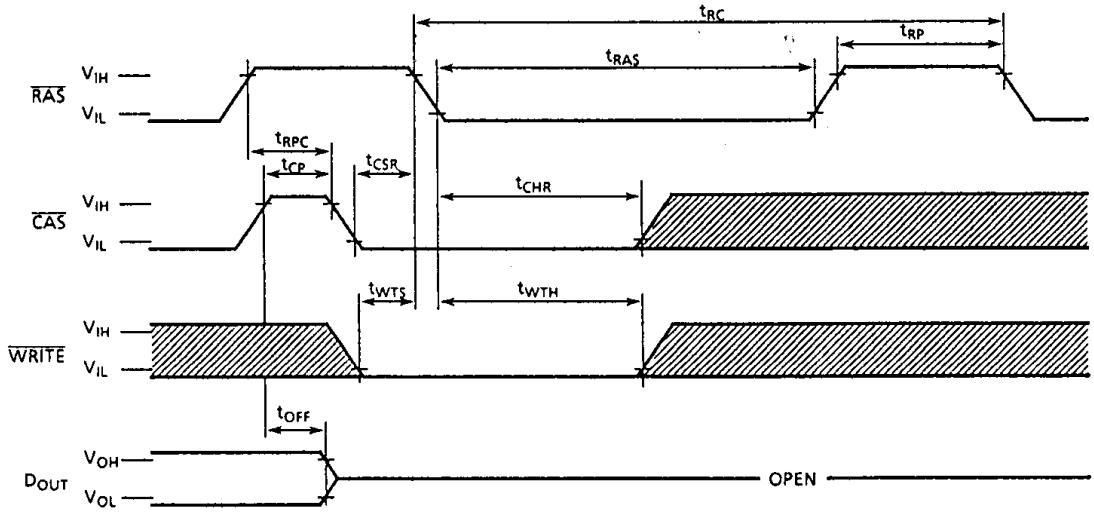
HIDDEN REFRESH CYCLE (WRITE)



CAS BEFORE RAS REFRESH COUNTER TEST CYCLE



WRITE, CAS BEFORE RAS REFRESH CYCLE



Note: D_{IN}, A0~A10 = "H" or "L"

▨ : "H" or "L"

TEST MODE

The TC514100AP/AJ/ASJ/AZ is the RAM organized 4,194,304 words by 1 bits, it is internally organized 524,288 words by 8 bits. In "Test Mode", data are written into 8 sectors in parallel and retrieved the same way. A_{10R}, A_{10C} and A_{0C} are not used. If, upon reading, all bits equal (all "1"s or "0"s), the data output pin indicates a "1". If any of the bits differed, the data output pin would indicate a "0". Fig.1 shows the block diagram of TC514100AP/AJ/ASJ/AZ. In "Test Mode", the 4M DRAM can be tested as if it were a 512K DRAM.

"$\overline{\text{WRITE}}$, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle" puts the device into "Test Mode". And "$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle" or "$\overline{\text{RAS}}$ Only Refresh Cycle" puts it back into "Normal Mode". In the Test Mode, "$\overline{\text{WRITE}}$, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle" performs the refresh operation with the internal refresh address counter. The "Test Mode" function reduces test times (1/8 in case of N test pattern).

BLOCK DIAGRAM IN THE TEST MODE

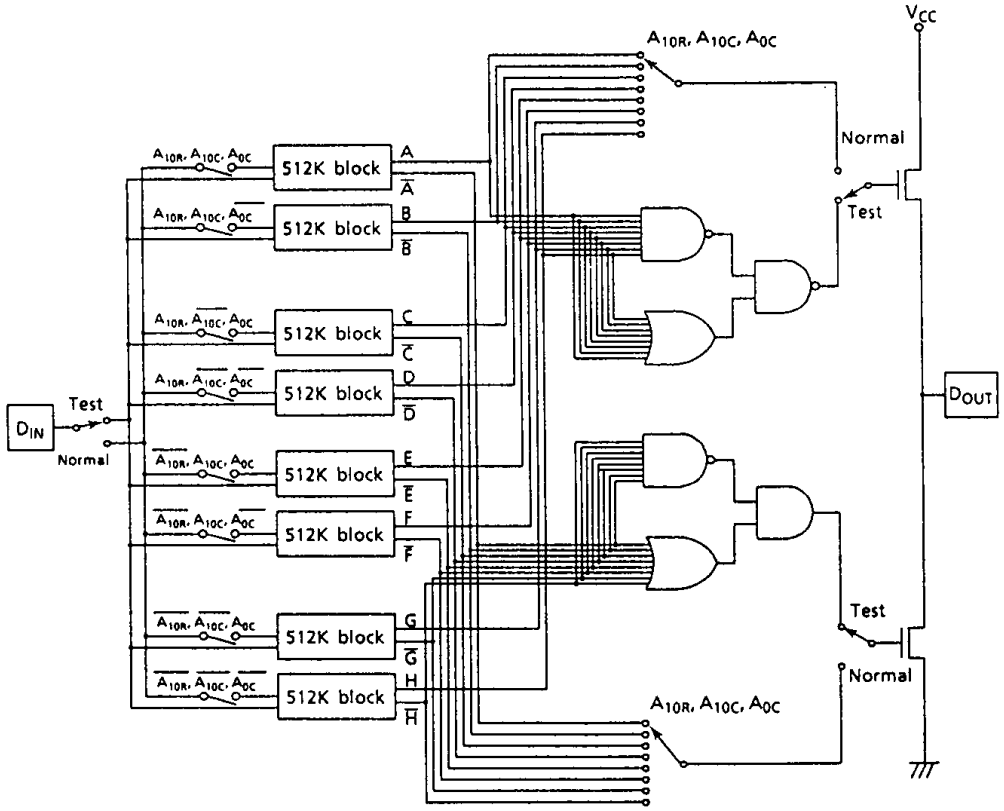


Fig. 1